

Carlos Mazure & Navab Singh
Institute of Microelectronics
Agency for Science, Technology
and Research (A*STAR)
Singapore

A*STAR encompasses



Research & Technology

- Science & Engineering Research Council (SERC)
 - 8 Research Institutes
- Biomedical Research Council (BMRC)
 - 9 Research Institutes
- National Platforms



Industry Development & Commercialisation

- Innovation & Enterprise (I&E)
- Venturing, Startups



Talent Development

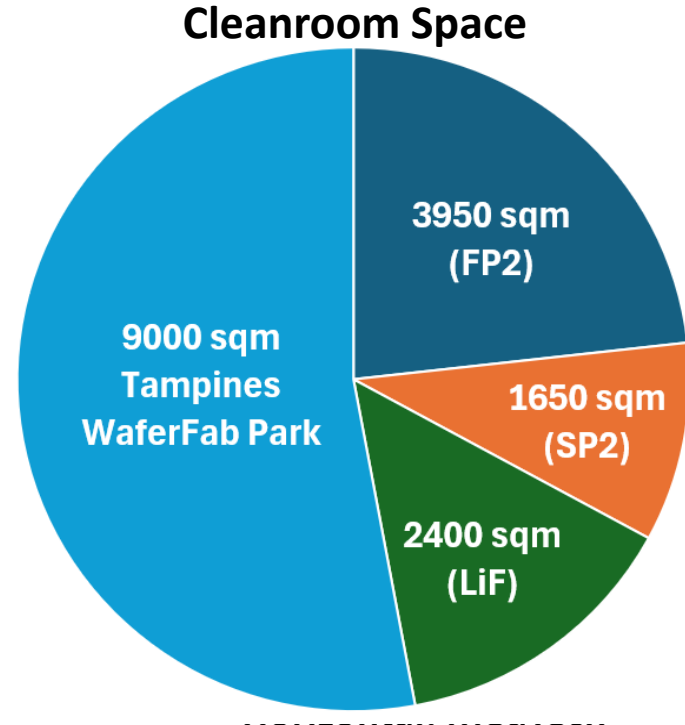
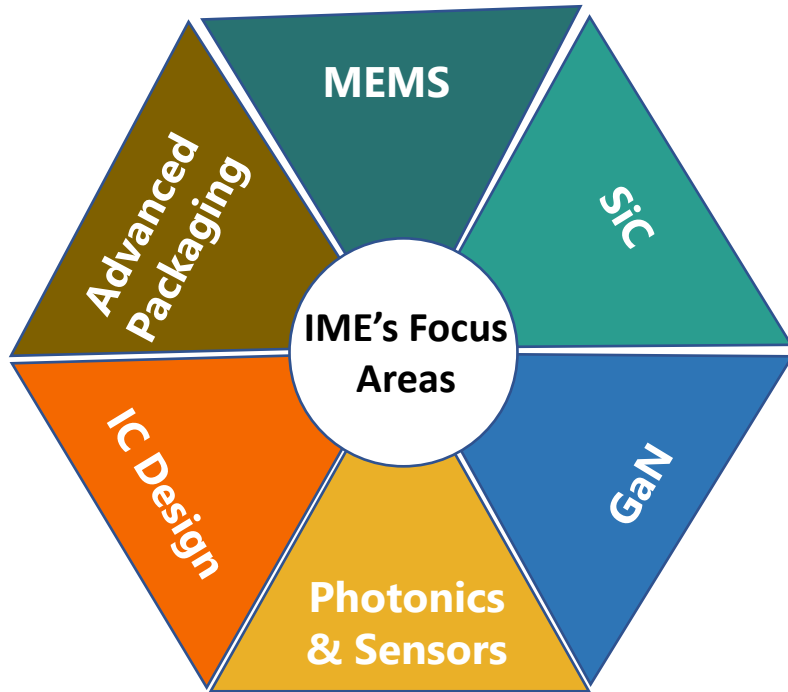
- A*STAR Graduate Academy

>6,000 Staff

>4,700 Researchers,
Engineers, and Technical
Support Staff

~37% from
>60 countries

Institute of Microelectronics: R&D & Prototyping in Industry-grade Facilities



Advanced Packaging

State-of-the-art 300mm R&D and prototyping line
Broad spectrum platform: W2W, C2W, chiplets, COP, SoW



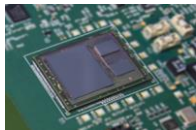
IME has a rich experience in Advanced Packaging



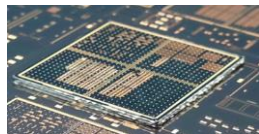
Our R&D is mostly driven by the needs of AI / high performance computing

2.5D/3D IC Packaging

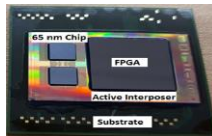
2.5D Passive Interposer



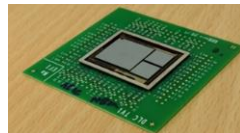
15 die stacking with TSV & μ -bump



Active Interposer

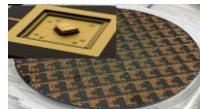


Embedded Fine Pitch Interconnect (bridge chip) Interposer

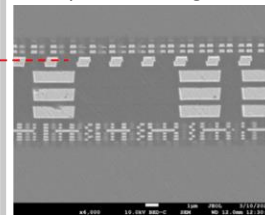


Bonding interface

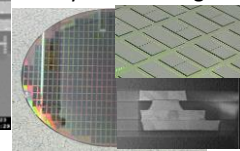
Quantum Ion Trap



Wafer-to-Wafer Hybrid Bonding



Chip-to-Wafer Hybrid Bonding



2013

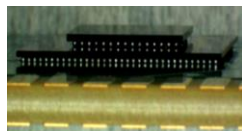
2015

2017

2019

2021

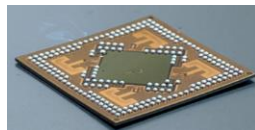
2023



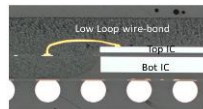
Fan-out Package-on-Package



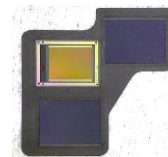
Multi-chip Fan-out Package



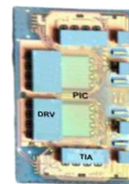
3D Antenna-in-Package



Ultra-thin Package-on-Package



Via-Last Through Silicon Via on multi-chip fan-out



Electronic Photonic Heterogenous Integration



Large (~3x reticle size) fan-out package for chiplet integration

Fan-out Packaging

Advanced Packaging Capabilities

Application/System Requirements

Data Centre/
HPC

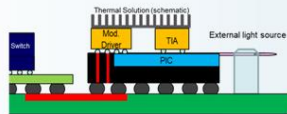
AI

IoT, 5G

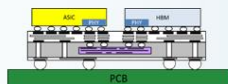
AR/VR

Automotive

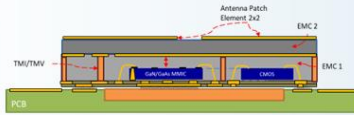
Package Architecture



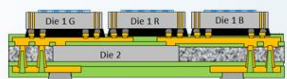
Electronic & Photonics Integration



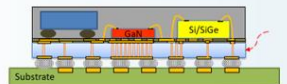
High Density 2.5D Pkg for AI SiP



Fan-out based RF module for 5G



AR/VR Display Module

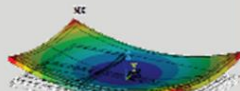


Si/SiC interposer for Radar module

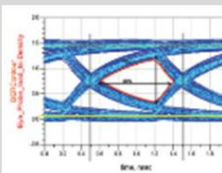


mmWave Antenna in FOWLP

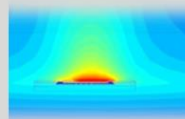
Models, PDK



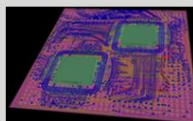
Mechanical



Electrical



Thermal

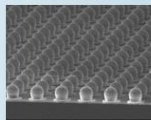


Package Design
(PDK)

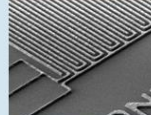
Adv. Pkg Modules



TSV



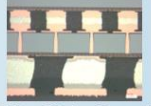
Micro-bumps



Fine Pitch RDL



Multi Layer RDL



Flip Chip Bonding

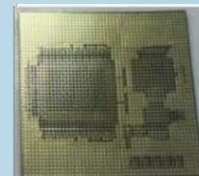


Cu-Cu Bonding

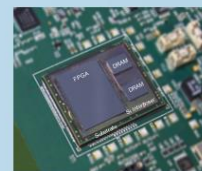
Process Integration, Materials Selection



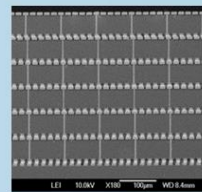
Packaging Platforms



FOWLP



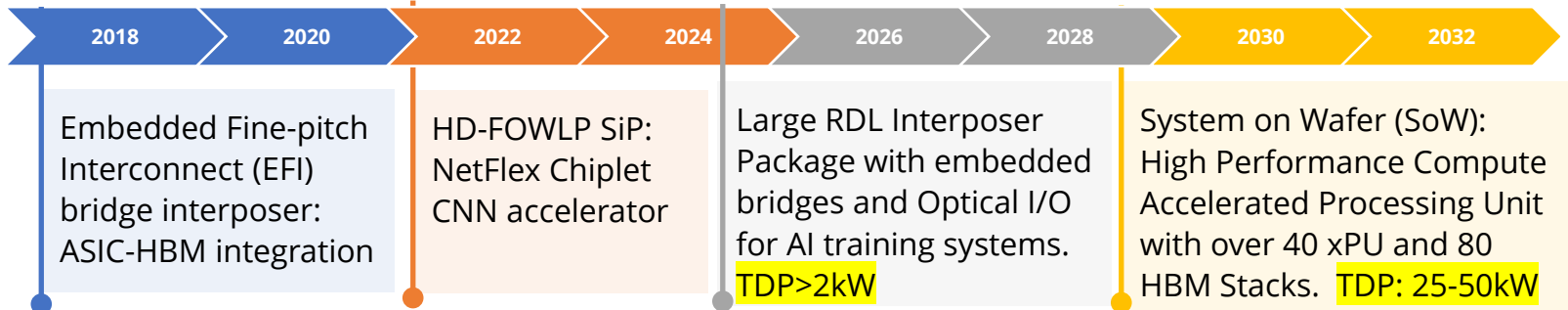
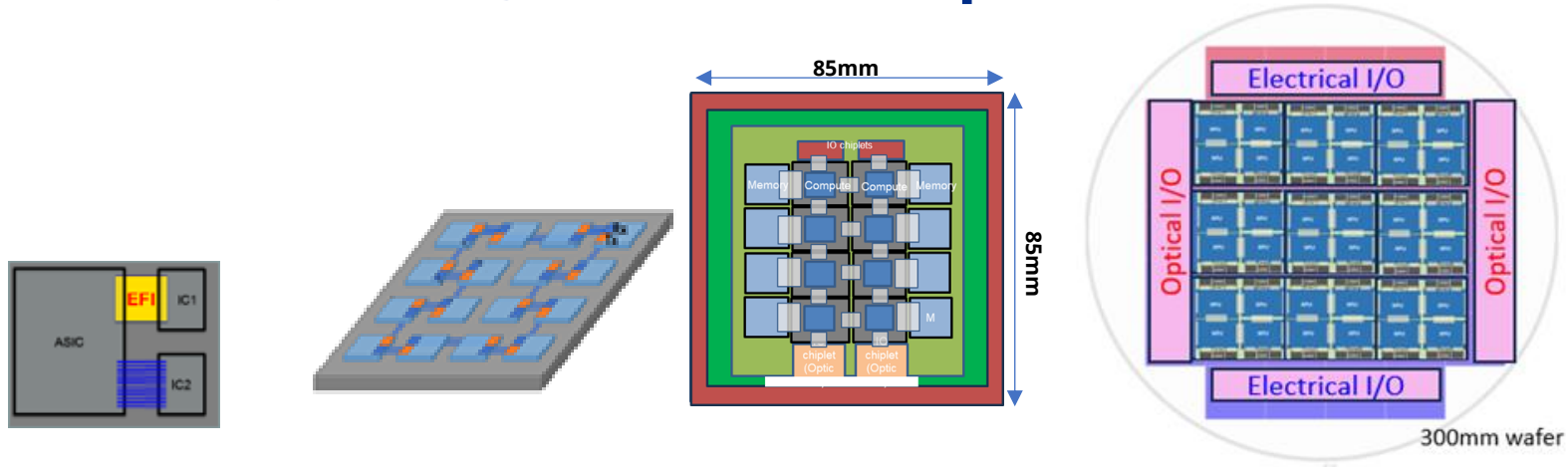
2.5D



3D Stacking

Development, prototyping & low volume mfg.

IME's Chiplet Integration Roadmap



Power Delivery and Thermal Cooling are Major Challenges for Ultra Large Systems

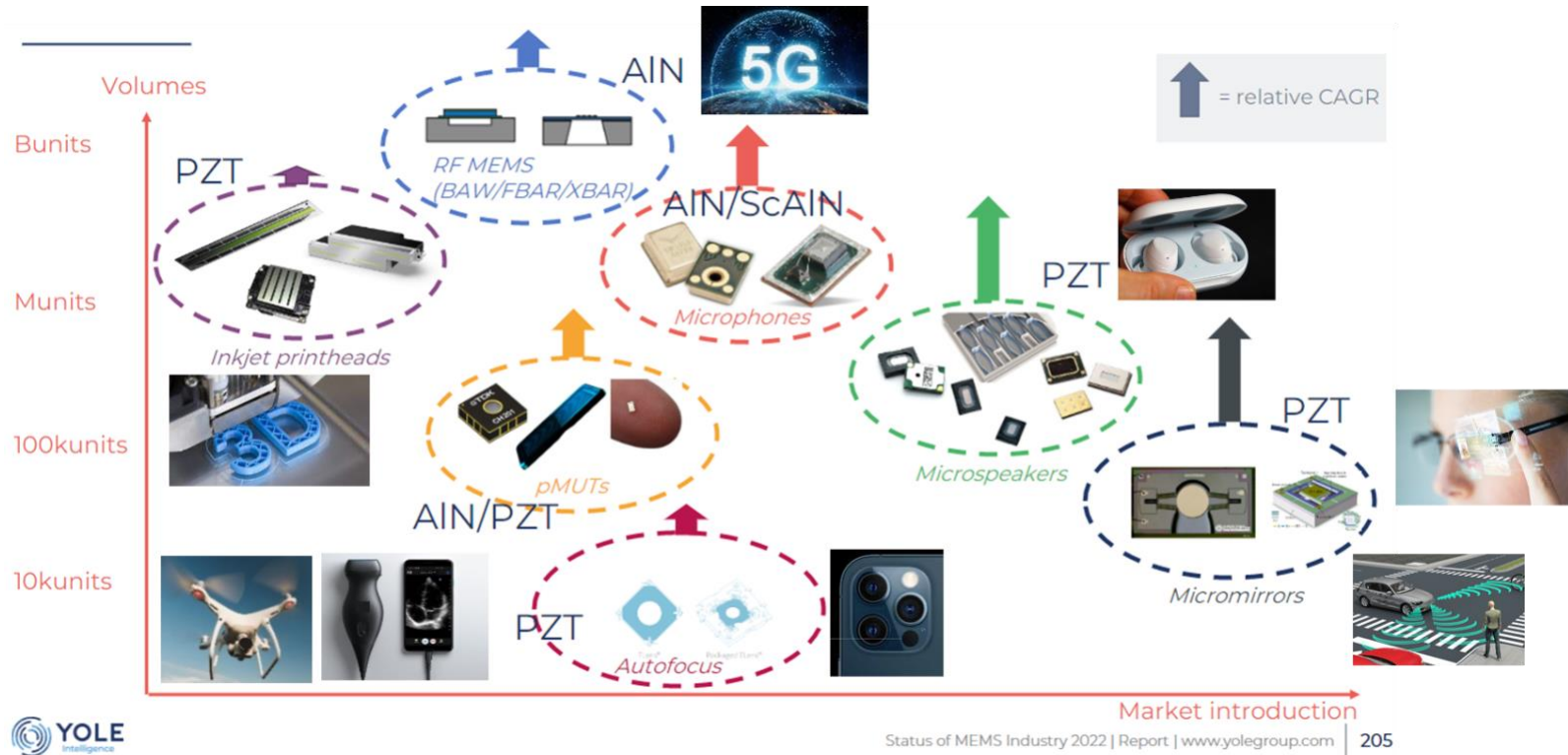
Piezo MEMS

Non-captive Lab-in-Fab

R&D and volume manufacturing in the same facility

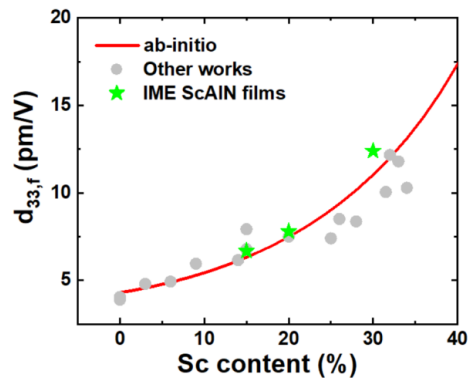
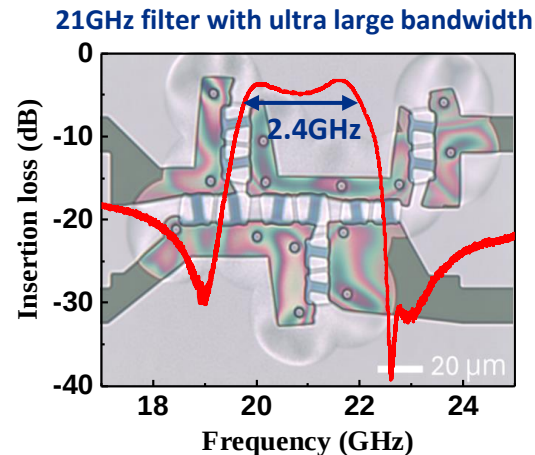
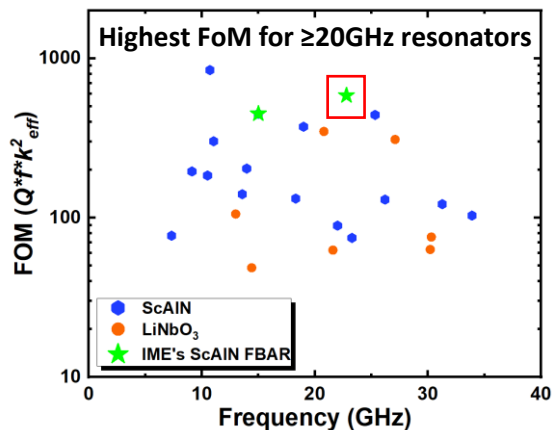
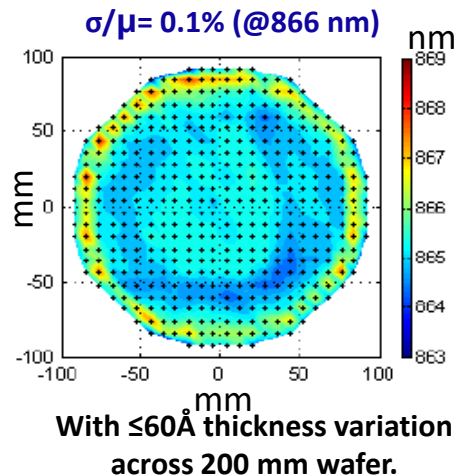
Fastest time-to-prototype for piezo-MEMS

Piezo-MEMS Platform addresses all Growth Areas



Its small size, low power consumption, and compatibility with semiconductor manufacturing processes make Piezo-MEMS an ideal solution for numerous applications.

Best-in-class piezo materials and platform technologies



Best-in-class ScAlN on Si wafer, characterized by highest Piezo coeff. d_{33}

Thin-film ScAlN platform
RF MEMS (GHz resonator & filter)
and resonator-based sensors

ScAlN/PZT on Si platform
for sensing and actuating

ScAlN on Si-on-nothing platform
for microfluidics and high density
PMUT arrays

PMUT using best of PZT & ScAlN

- TX sensitivity: 4x higher for PZT
- RX sensitivity: 10x higher for ScAlN
- **Best combination: TX-PZT & RX-ScAlN.**



SiC

Most advanced 200mm R&D and prototyping line
Non captive process and device development
Complete ecosystem from epitaxy thru power module

Silicon Carbide Technology Platform



- SiC crystal
- SmartSiC™
- via procuring substrates



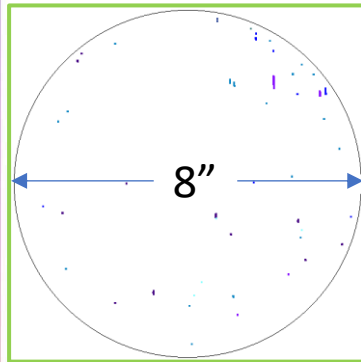
- Si-/C-face SiC
- Trench-filled SiC Epitaxy



- Si-/C-face Trench Gate MOSFET w/wo SJs
- Si-/C face Junction Barrier Schottky Diode
- SiC CMOS (Planar Gate/FINFET) Drivers
- IGBT with modified SmartSiC™

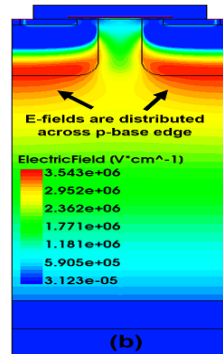


- Double-Sided Cooling, DBC-free package, 3-Phase solutions
- Co-Optimized Device to Package
- Module with integrated gate drivers

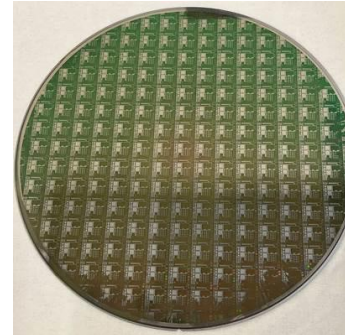


Post epitaxy Candela 8520 scan,
Total Killer defect density $\leq 0.5/\text{cm}^2$

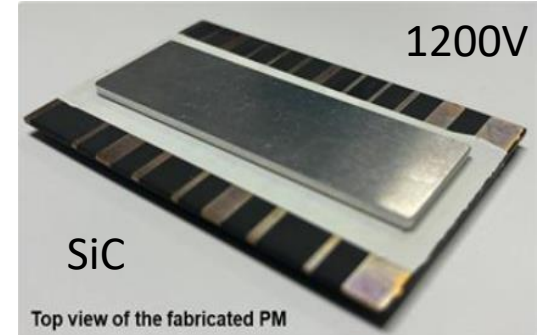
- Triangle
- Shallow Triangle
- Pit Triangle
- Downfall
- Carrot
- Step Bunching
- Pit
- Stacking Fault
- Bar Stacking Fault
- BPD
- PL Spot
- Bump



Device TCAD



Fully fabricated 8" wafer



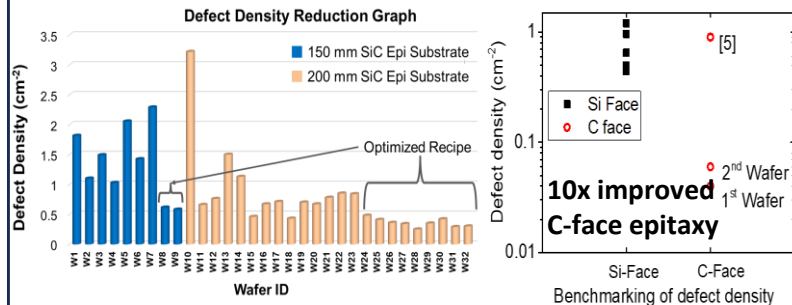
Top view of the fabricated PM

6-in-1, 3-phase SiC power module

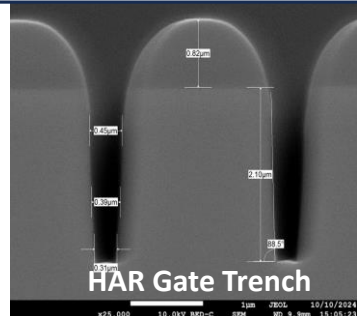
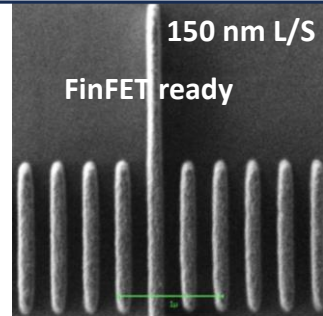
Speciality of Our 200 mm Open Innovation SiC Pilot



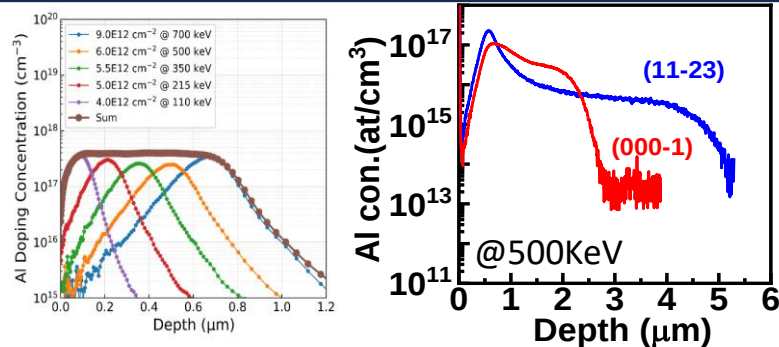
**ASM LPE 108 with
Candela 8520.**
“Extremely low killer
defects & Excellent
Thickness and Doping
uniformity”



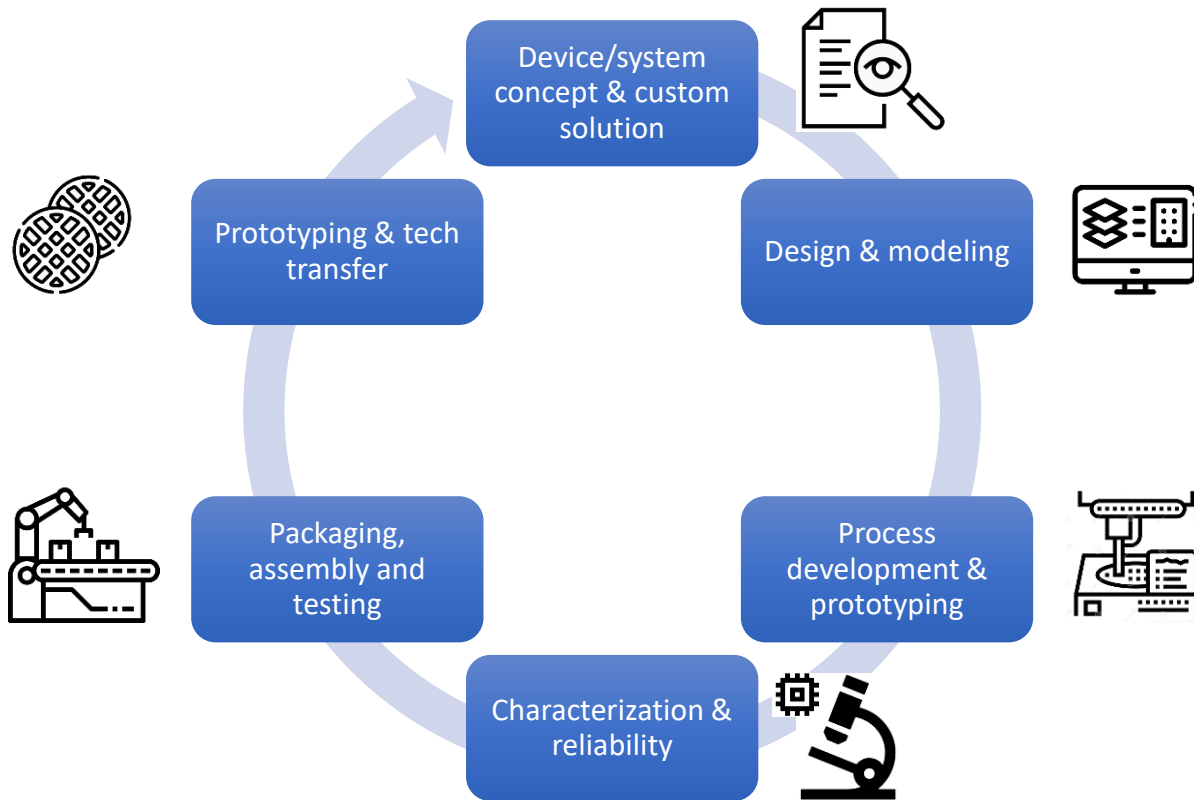
**ASML PAS5500/850C
with TEL Act-8.**
“110nm resolution in a
SiC line with transparent
wafer handling
capability”



Nissin IMPHEAT-II with integrated XRD.
 “Channeling implant for device innovations reducing manufacturing cost”



Summary: Value Proposition





THANK YOU

For more information, visit www.a-star.edu.sg

Email contact: Navab@ime.a-star.edu.sg